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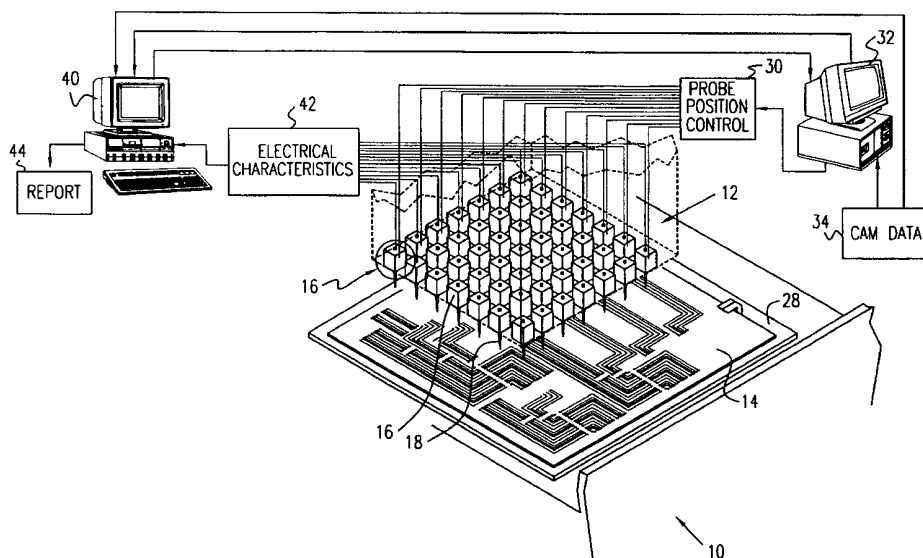
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(54) Title: APPARATUS AND METHOD FOR ELECTRICAL TESTING OF ELECTRICAL CIRCUITS



(57) Abstract: Apparatus for electrical testing of electrical circuits includes an array of probes arranged for selective engagement with portions of electrical circuits to be tested, testing circuitry associated with the array of probes for sensing electrical characteristics of the electrical circuits engaged by the array of probes, and control circuitry associated with the array of probes for causing engagement between selected ones of the array of probes with selected ones of the portions of electrical circuits to be tested. The array of probes includes at least two static probe assemblies arranged in a fixed array, and the static probe assemblies include a selectively positionable probe element and a probe element positioner. The apparatus is employed to test electrical circuits during fabrication.



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INTERNATIONAL SEARCH REPORT

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A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G01R1/073

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 G01R

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	<p>GB 2 294 365 A (BATH SCIENTIFIC) 24 April 1996 (1996-04-24)</p> <p>abstract page 7, paragraph 2 - paragraph 3 page 8, paragraph 2 -page 9, paragraph 1; figures 1,3,4</p> <p style="text-align: center;">---</p> <p style="text-align: center;">-/--</p>	<p>1-3,7,9, 12,13, 38-40, 45,48, 49,51, 54-56,59</p>

Further documents are listed in the continuation of box C.

Patent family members are listed in annex.

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- *&* document member of the same patent family

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
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A	column 3, line 23 -column 6, line 22; figures 1,2 ---	60
X	EP 0 293 497 A (IBM DEUTSCHLAND) 7 December 1988 (1988-12-07)	1-3,9, 13,15, 16,20, 24,51, 52,59
A	column 2, line 22 - line 31; figures 1,5 ---	60
X	EP 0 468 153 A (ATG ELECTRONIC) 29 January 1992 (1992-01-29)	1-13, 15-24, 26-36
A	column 7, line 32 -column 8, line 35 column 10, line 1 -column 11, line 26; figures 1-5 ---	38-49, 51-59
X	DE 195 03 329 A (ITA INGENIEURSBÜRO) 8 August 1996 (1996-08-08)	15,17, 18,20, 23-27, 29,30, 32, 35-37, 60-62, 70,71
	column 2, line 17 - line 26; figures 1-7 column 2, line 35 - line 39 column 2, line 55 - line 65 column 3, line 10 - line 48 column 4, line 16 - line 53 column 5, line 4 -column 7, line 28; figures 1-7 ---	
A	DE 198 17 802 A (MARCO SYSTEMANALYSE) 28 October 1999 (1999-10-28) cited in the application column 3, line 25 - line 32 column 3, line 61 - line 68 column 4, line 41 - line 53; figures 1,6 -----	60, 63-66, 68-70

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

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